

**Dual 4-Input NAND Gate****Features**

- Typical Propagation Delay
  - 6ns at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $C_L = 50pF$
- Exceeds 2kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-Resistant CMOS Process and Circuit Design
- Speed of Bipolar FAST™/AS/S with Significantly Reduced Power Consumption
- Balanced Propagation Delays
- AC Types Feature 1.5V to 5.5V Operation and Balanced Noise Immunity at 30% of the Supply
- $\pm 24mA$  Output Drive Current
  - Fanout to 15 FAST™ ICs
  - Drives  $50\Omega$  Transmission Lines

**Description**

The CD74AC20 and 'ACT20 are dual 4-input NAND gates that utilize Advanced CMOS Logic technology.

**Ordering Information**

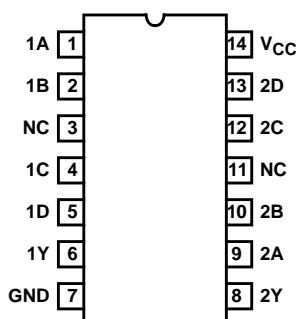
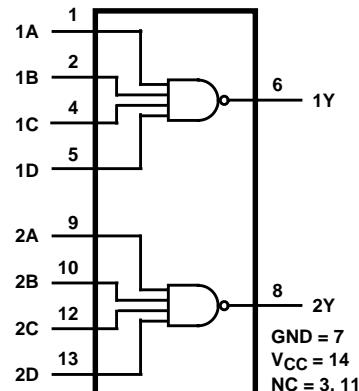
PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD74AC20E	-55 to 125	14 Ld PDIP
CD74AC20M	-55 to 125	14 Ld SOIC
CD54ACT20F3A	-55 to 125	14 Ld CERDIP
CD74ACT20E	-55 to 125	14 Ld PDIP
CD74ACT20M	-55 to 125	14 Ld SOIC

## NOTES:

1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer and die for this part number is available which meets all electrical specifications. Please contact your local TI sales office or customer service for ordering information.

**Pinout**

CD54ACT20  
(CERDIP)  
CD74AC20, CD74ACT20  
(PDIP, SOIC)  
TOP VIEW

**Functional Diagram****TRUTH TABLE**

INPUTS				OUTPUTS
nA	nB	nC	nD	nY
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H
H	H	H	H	L

X = Don't Care

**Absolute Maximum Ratings**

DC Supply Voltage, V <sub>CC</sub> .....	-0.5V to 6V
DC Input Diode Current, I <sub>IK</sub>	
For V <sub>I</sub> < -0.5V or V <sub>I</sub> > V <sub>CC</sub> + 0.5V .....	±20mA
DC Output Diode Current, I <sub>OK</sub>	
For V <sub>O</sub> < -0.5V or V <sub>O</sub> > V <sub>CC</sub> + 0.5V .....	±50mA
DC Output Source or Sink Current per Output Pin, I <sub>O</sub>	
For V <sub>O</sub> > -0.5V or V <sub>O</sub> < V <sub>CC</sub> + 0.5V .....	±50mA
DC V <sub>CC</sub> or Ground Current, I <sub>CC</sub> or I <sub>GND</sub> (Note 3)	±100mA

**Thermal Information**

Thermal Resistance (Typical, Note 5)	θ <sub>JA</sub> (°C/W)
PDIP Package .....	90
SOIC Package .....	175
Maximum Junction Temperature (Plastic Package) .....	150°C
Maximum Storage Temperature Range .....	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s) .....	300°C

**Operating Conditions**

Temperature Range, T <sub>A</sub> .....	-55°C to 125°C
Supply Voltage Range, V <sub>CC</sub> (Note 4)	
AC Types .....	1.5V to 5.5V
ACT Types .....	4.5V to 5.5V
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub> .....	0V to V <sub>CC</sub>
Input Rise and Fall Slew Rate, dt/dv	
AC Types, 1.5V to 3V .....	50ns (Max)
AC Types, 3.6V to 5.5V .....	20ns (Max)
ACT Types, 4.5V to 5.5V .....	10ns (Max)

*CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.*

## NOTES:

3. For up to 4 outputs per device, add ±25mA for each additional output.
4. Unless otherwise specified, all voltages are referenced to ground.
5. θ<sub>JA</sub> is measured with the component mounted on an evaluation PC board in free air.

**DC Electrical Specifications**

PARAMETER	SYMBOL	TEST CONDITIONS		V <sub>CC</sub> (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
		V <sub>I</sub> (V)	I <sub>O</sub> (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
<b>AC TYPES</b>											
High Level Input Voltage	V <sub>IH</sub>	-	-	1.5	1.2	-	1.2	-	1.2	-	V
				3	2.1	-	2.1	-	2.1	-	V
				5.5	3.85	-	3.85	-	3.85	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	1.5	-	0.3	-	0.3	-	0.3	V
				3	-	0.9	-	0.9	-	0.9	V
				5.5	-	1.65	-	1.65	-	1.65	V
High Level Output Voltage	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.05	1.5	1.4	-	1.4	-	1.4	-	V
			-0.05	3	2.9	-	2.9	-	2.9	-	V
			-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-4	3	2.58	-	2.48	-	2.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	V

# CD74AC20, CD54/74ACT20

## DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V <sub>CC</sub> (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
		V <sub>I</sub> (V)	I <sub>O</sub> (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
Low Level Output Voltage	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.05	1.5	-	0.1	-	0.1	-	0.1	V
			0.05	3	-	0.1	-	0.1	-	0.1	V
			0.05	4.5	-	0.1	-	0.1	-	0.1	V
			12	3	-	0.36	-	0.44	-	0.5	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	V
Input Leakage Current	I <sub>I</sub>	V <sub>CC</sub> or GND	-	5.5	-	±0.1	-	±1	-	±1	µA
Quiescent Supply Current SSI	I <sub>CC</sub>	V <sub>CC</sub> or GND	0	5.5	-	4	-	40	-	80	µA
<b>ACT TYPES</b>											
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	2	-	2	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	V
Low Level Output Voltage	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.05	4.5	-	0.1	-	0.1	-	0.1	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	V
Input Leakage Current	I <sub>I</sub>	V <sub>CC</sub> or GND	-	5.5	-	±0.1	-	±1	-	±1	µA
Quiescent Supply Current SSI	I <sub>CC</sub>	V <sub>CC</sub> or GND	0	5.5	-	4	-	40	-	80	µA
Additional Supply Current per Input Pin TTL Inputs High 1 Unit Load	ΔI <sub>CC</sub>	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	2.4	-	2.8	-	3	mA

### NOTES:

6. Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
7. Test verifies a minimum 50Ω transmission-line-drive capability at 85°C, 75Ω at 125°C.

### ACT Input Load Table

INPUT	UNIT LOAD
All	0.27

NOTE: Unit load is ΔI<sub>CC</sub> limit specified in DC Electrical Specifications Table, e.g., 2.4mA max at 25°C.

# CD74AC20, CD54/74ACT20

**Switching Specifications** Input  $t_r, t_f = 3\text{ns}$ ,  $C_L = 50\text{pF}$  (Worst Case)

PARAMETER	SYMBOL	$V_{CC} (\text{V})$	-40°C TO 85°C			-55°C TO 125°C			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
<b>AC TYPES</b>									
Propagation Delay, Input to Output	$t_{PLH}, t_{PHL}$	1.5	-	-	139	-	-	153	ns
		3.3 (Note 9)	4.4	-	15.5	4.3	-	17.1	ns
		5 (Note 10)	3.1	-	11.1	3.1	-	12.2	ns
Input Capacitance	$C_I$	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	$C_{PD}$ (Note 11)	-	-	48	-	-	48	-	pF
<b>ACT TYPES</b>									
Propagation Delay, Input to Output	$t_{PHL}$ $t_{PLH}$	5 (Note 10)	3.5	-	12.3	3.4	-	13.5	ns
Input Capacitance	$C_I$	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	$C_{PD}$ (Note 11)	-	-	48	-	-	48	-	pF

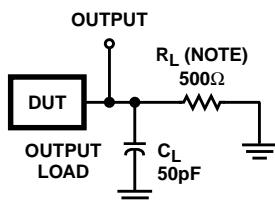
NOTES:

8. Limits tested at 100%.
9. 3.3V Min at 3.6V, Max at 3V.
10. 5V Min at 5.5V, Max at 4.5V.

11.  $C_{PD}$  is used to determine the dynamic power consumption per gate.

$$\text{AC: } P_D = V_{CC}^2 f_i (C_{PD} + C_L)$$

$$\text{ACT: } P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC} \text{ where } f_i = \text{input frequency}, C_L = \text{output load capacitance}, V_{CC} = \text{supply voltage}.$$



NOTE: For AC Series Only: When  $V_{CC} = 1.5\text{V}$ ,  $R_L = 1\text{k}\Omega$ .

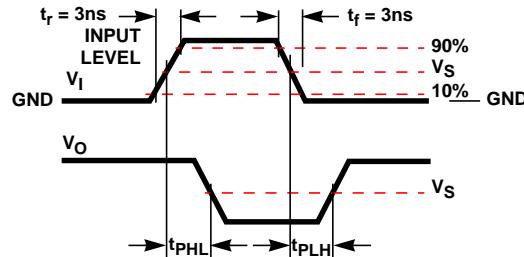


FIGURE 2.

	AC	ACT
Input Level	$V_{CC}$	3V
Input Switching Voltage, $V_S$	$0.5 V_{CC}$	1.5V
Output Switching Voltage, $V_S$	$0.5 V_{CC}$	$0.5 V_{CC}$

FIGURE 1. PROPAGATION DELAY TIMES

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